



Tuesday, April 25, 2017

08:00 - 17:00	Registration On Site					
	Room 305A	Room 305B	Room 307A	Room 307B	Room 302A	
Workshops						
09:20 - 10:00	WS_TU101: GaAs and GaN Manufacturing Technology at SAIC (158) Xiamen San'an Integrated Circuit Co.	WS_TU102: Multilayer PTFE PCBs in 5G Technology (161) Taconic Advanced Material (Suzhou) Co. Ltd.	WS_TU103: Pave Your Way for the 5G Era (147) National Instruments	WS_TU104: Advanced III/V MMIC Process Roadmaps for Terahertz Applications (163) Sichuan YiFeng Electronic Science & Technology Co. Ltd. Workshop		
10:00 - 10:20	Tea Break (Exhibit Hall)					
10:30 - 12:00	Plenary Session Room 302: Featuring Keynote Speaker Peter Rabbeni, GLOBALFOUNDRIES. Guest Speakers: Satish Dhanasekaran, Keysight Technologies; Corbett Rowell, Rohde & Schwarz; Jason White, National Instruments.					
12:00 - 13:00	Lunch Break					
Technical Sessions						
	5G	Test & Measurement	Radar/Communications	Amplifiers	RF/Microwave	
13:00 - 13:20	TU_101: Polar Code for 5G Mobile Communication (24) Shi Xiaofeng, Rohde & Schwarz	TU_102: Advanced Materials Measurement Techniques for Permittivity and Permeability (5) Ryoji Takizawa, Keysight	TU_103: 900 W GaN-HEMT Transistor for L-Band Radar Applications (23) Weishu Zhou, Microsemi	TU_104: High Linear CMOS Power Amplifier and Tracker for LTE Advanced Applications (4) Florinel Balteanu, Skyworks	TU_105: Practical Considerations for Load-Dependent X-Parameters Extraction with Harmonic Impedance Control of a 10 W GaN Power Transistor (68) Di Liu, Keysight	Exhibit Hall Open 10:00 - 17:30
13:25 - 13:45	TU_201: Ultra-Wideband Signal Phase and Amplitude Calibration Method for High Performance 5G mmWave Device Testing (35) Li Feng, Keysight	TU_202: Introduction to Real-Time Spectrum Monitoring (88) Fangze Tu, National Instruments	TU_203: EM/Circuit Co-Simulation of T/R Front-End Module and Actively Scanned Antenna Array (44) Milton Lien, AWR	TU_204: A Novel Impedance Flattening Network for Wideband Doherty Power Amplifier at 3.4 to 3.8 GHz (82) Rui Ma, Mitsubishi Electric Research Labs	TU_205: Embedded Thin Film Planar Resistors in 5G Power Dividers for Improved High Speed Signal Integrity (19) Helena Li, Shanghai Genronics Electronics. Ltd.	
13:50 - 14:10	TU_301: MIMO OTA Certification Testing Solution: Multi-Probe Method (71) Andy Zhang, Hwa-Tech Information System Co.	TU_302: New Method for Debugging Crosstalk Issues in Your Design (40) Min-Jie Chong, Keysight	TU_303: RF Environment Generation for Radar and Receiver Test (99) Steffen Heuel, Rohde & Schwarz	TU_304: A Design of High Efficiency GaN on Si 3 Way Doherty Amplifier for Base Station Application (116) Xin Liu, MACOM	TU_305: Solid-State RF Energy in 2017: The Volume Breakthrough is Finally There, is it Not? Moderator: Klaus Werner, RF Energy Alliance, Presentation and Panel Panelists: Pinglu Chen, Ampleon Mark Murphy, MACOM Dong Wu, NXP Art Aguayo, Rogers Corp. Yinghao Zhuo, Innovation Technologies James Huang, Huber+Suhner	
14:15 - 14:35	TU_401: RF SOI Technology for Reliable 5G Beamforming (92) Charles Gui, Peregrine Semiconductor	TU_402: The Latest Trend for Mobile FEM and Noise Figure Measurements (51) Gu HongLiang, Keysight	TU_403: Automotive Radar Interference Test (100) Steffen Heuel, Rohde & Schwarz	TU_404: The New Frontier in Solid State Power Amplifiers: The Spatial Power Amplifier (60) Maurizio D'Antoni, University of Rome		
14:40 - 15:00	TU_501: 5G Device Design Verification and Test Challenges (28) Li Xin, Keysight	TU_502: New Approach of Building RF PA/FEM Test Systems Jianhui Wang, Keysight	TU_503: Modeling Large Phased-Array Antenna Systems With an Advanced Behavioral Model and Simulated/Measured Radiating Elements (43) Gent Papparisto, AWR	TU_504: Design of MMIC Class-E Adaptive Bias Power Amplifier with Built-In Linearizer using 0.5 μm GaAs E-pHEMT Technology (111) Shanthi. P. R.V. College of Engineering		
15:00 - 15:20	Tea Break: Exhibition Floor					
Workshops						
	Measurement & Modeling	5G	High-Speed Digital	Semiconductors	Test & Measurement	
15:20 - 16:00	WS_TU201: From Wave-Based Load-Pull to Behavioral Nonlinear Models (11) Focus Microwaves	WS_TU202: Verizon 5G and 3GPP New Radio (NR) Generation and Analysis (102) Rohde & Schwarz	WS_TU203: Via Structure Optimization for Pre-layout PCIe Channel Design (53) ANSYS	WS_TU204: E-Foundry Model Provides New Opportunity (133) Chengdu HiWafer Semiconductor	WS_TU205: New High Performance Test Cable Assemblies, Millimeter Wave Integrated Multi-Pin Connector Harness Assemblies & Aerospace High Speed Data Master Cable Assemblies (138) Mitron	
16:05 - 16:45	WS_TU301: Load Pull: A Critical Tool For Model Extraction, Validation and Design (48) Maury Microwave	WS_TU302: Portable MIMO Testing Platform Based on the Technology of Software Defined Radio (128) Sample Technology Shanghai	WS_TU303: Interfacing FPGA with High-Speed Data Converter Using Parallel and Serial Interface (108) e2V	WS_TU304: Sanan III-V Semiconductor Foundry (159) Xiamen San'an Integrated Circuit Co.	WS_TU305: Massive MIMO Prototype and MIMO OTA Test (136) Keysight	
16:50 - 17:30	WS_TU401: Accelerating Design Cycle Time of Key RF FEM Circuit Blocks Through Innovative Modeling Methods (81) GLOBALFOUNDRIES	PN_TU402-PANEL: Which Technology is Better for the First 5G Systems: Massive MIMO sub-6 GHz or mmWaves? Moderator: Patrick Hindle, MWJ	WS_TU403: High-Speed Simulation & Measurement (137) CST	WS_TU404: GaN RF Power Devices (146) Dynax Semiconductor	WS_TU405: Multiport Automatic Testing System Based on Switch Matrix with High Reliability (141) Mini-Circuits	
17:30	Welcome Reception for Conference Delegates (Badge & Ticket Required)					

Wednesday, April 26, 2017

	Room 305A	Room 305B	Room 307A	Room 307B	Room 302A	
08:00 - 05:00	Registration On Site					
Technical Session						
	Test & Measurement	Systems Engineering	IoT	5G	RF & Microwave	
09:00 - 09:20	WE_101: Techniques for Extending Microwave Frequency Instruments for mmWave Measurements <i>(78) Wei Lin, National Instruments</i>	WE_102: Addressing Multi-Channel, Wide-Band Test and Data Management in 5G <i>(25) Sheri DeTomas, Keysight</i>	WE_103: Electromagnetic and Structural Co-Design of a Smart Watch <i>(91) Cier Siang Chua, CST</i>	WE_104: New Wireless Technologies for Tomorrow's Connected Devices <i>(55) David Hall, National Instruments</i>	WE_105: Advanced Techniques for Spurious Search in RF and Microwave Devices <i>(6) Martin Schmaehling, Rohde & Schwarz</i>	
09:25 - 09:45	WE_201: Challenges and Test Solution of Low Power Wide Area Network <i>(30) Jian Li, Keysight</i>	WE_202: Building a Multi-GHz Real-Time RF Streaming System <i>(98) Shivansh Chaudhary, National Instruments</i>	WE_203: Channel Emulation for RFID Baseline Test <i>(112) Hui Shao, JX Instrumentation Co. Ltd.</i>	WE_204: Compact Phased Array with Beamforming Network for 5G MIMO System at 60-GHz on Liquid Crystal Polymer Substrate <i>(3) Wu Jiarui, Keysight</i>	WE_205: A Multi-Offset PLL Synthesizer with Phase Detector Noise Floor Degeneration <i>(29) Dr. Alexander Chenakin, Micro Lambda Wireless Inc.</i>	
09:45 - 10:05	Tea/Coffee Break - Exhibition Floor					
	High Speed Digital	Test & Measurement	EMC/EMI	5G	RF & Microwave	
10:10 - 10:30	WE_301: Timing Mistakes in High-Speed PCB Design <i>(9) Wu Jun, Edadoc</i>	WE_302: Novel Modeling Method Based on Field Measurement Data in OTA Chamber for UE Performance Test <i>(74) Huaizhi Yang, Keysight</i>	WE_303: Real-Time Measuring Equipment Optimized for Faster Detection of Critical EMI Signals <i>(18) Volker Janssen, Rohde & Schwarz</i>	WE_304: Introduction to 802.11ax: High Efficiency Wi-Fi <i>(83) Alejandro Burritica, National Instruments</i>	WE_305: High Performance Material Considerations for Use in Wireless Communications Infrastructure <i>(126) Art Aguayo, Rogers Corp.</i>	Exhibition Hours 09:00 to 17:30
10:35 - 10:55	WE_401: Fast and Accurate Measurement of PCB Quality Parameters <i>(63) Yang Hongwen, Rohde & Schwarz</i>	WE_402: Advanced PA Test Techniques: Advanced Technologies for DPD, ET and Measurement Acceleration <i>(85) Alejandro Burritica, National Instruments</i>	WE_403: Protecting the Next Generation Technologies-5G, IoT and Automotive Through EMC Solutions <i>(94) Sangam Baigiar, AR RF/Microwave Instrumentation</i>	WE_404: Software Defined Radio Techniques Applied to 5G Emulation <i>(77) Tom Higgins, Keysight</i>	WE_405: CMOS and SOI for RF Modules <i>(33) Malcolm Smith, AnalogSmith Design Solutions LLC</i>	
11:00 - 11:20	WE_501: Signal Integrity Measurement Using a Vector Network Analyzer <i>(38) Fei Yu, Rohde & Schwarz</i>	WE_502: Millimeter Wave OTA Test Challenges <i>(89) Prasadh Ramachandran, Keysight</i>	WE_503: SmartTone Proposal of EMC <i>(69) Andy Zhang, Hwa-Tech Information System Co.</i>	WE_504: 5G Antenna for Mobile Terminal Device Application <i>(113) Bin Yu, Speed Wireless Technology Co. Ltd.</i>	WE_505: Very High Efficiency High Power Schottky Diode Frequency Doubler Operating at 180 to 190 GHz <i>(75) Michael Crowley, Farran Technology</i>	
11:25 - 11:45	WE_601: PAM-4 Challenges and Testing in 400G Ethernet <i>(22) Li Kai, Keysight</i>	WE_602: Distortion Measurements on Radio Front-End (RFFE) Components and Chains <i>(121) Fabricio Dourado, Rohde & Schwarz</i>	WE_603: Discussion of EMC Test Technology for Automotive Electronics <i>(101) Cinya Tu, Institute of EMC & Electronic Measurement, EVERFINE Instrument Co. Ltd.</i>	WE_604: Verification of Beamforming Devices with OTA (Over-the-Air) Power Sensors <i>(115) Frank W. Thümmel, Rohde & Schwarz</i>	WE_605: Broadband Microwave Frequency Doublers with Improved Harmonic Suppression Based on Quasi-Vertical GaAs Shottky Diodes <i>(50) Nikolay Drobotov, TUSUR</i>	
12:00 - 13:00	Lunch Break - Exhibition Floor					
Workshops						
	Measurement & Modeling	5G	RF & Microwave/IoT	RF & Microwave		
13:00 - 13:40	WS_WE101: The Next Generation WLAN Standard and Overcoming the Test Challenges <i>(95) Keysight</i>	WS_WE102: 60 GHz Wireless Systems with Circuit/EM Co-Simulation <i>(64) ANSYS</i>	WS_WE103: Narrowband IoT: Operation Modes and Their Use-Cases <i>(134) Keysight</i>	WS_WE104: High Performance Material Considerations for Use in Wireless Communications Infrastructure <i>(151) Rogers Corporation</i>	WS_WE105: Key Design Solutions for High-Reliability Semiconductors with e2v <i>(155) e2v</i>	
13:45 - 14:25	WS_WE201: Simulation of a Large Cassegrain Antenna with an FSS Subreflector <i>(46) ANSYS</i>	WS_WE202: 20 W Fully Integrated 3.5 GHz GaN Doherty MMICs for 5G Applications <i>(132) Ampleon</i>	PN_WE203_PANEL: Trends in Mobile Infrastructure <i>Moderator: Gary Lerude, MWJ</i>	WS_WE204: New Challenges for Next-Generation Vehicles <i>(127) National Instruments</i>	WS_WE205: Advanced PCB Rule Checking for Signal Integrity and EMC <i>(160) CST</i>	Poster Session 14:00 to 15:00
14:30 - 14:50	Tea/Coffee Break - Exhibition Floor					
	RF & Microwave	Measurement & Modeling	5G			
14:50 - 15:30	WS_WE301: Designs of GaN on Silicon Doherty PAs for Commercial Base Station Application <i>(61) MACDM</i>	WS_WE302: VNA Based Measurements and Nonlinear Modeling for Efficient RF PA Circuit Design <i>(47) Maury Microwave</i>	WS_WE303: Wideband Amplitude and Phase Control Matrix for 5G MIMO Channel Simulation <i>(139) Mitron</i>	WS_WE304: Cardiff Model+ Investigating Bias and Frequency Interpolation Using RAPID Behavioral Model Extraction <i>(152) Focus Microwaves</i>	WS_WE305: The Future Outlook of RF GaN: Applications and Performance <i>(150) Richardson RFPD</i>	
15:35 - 16:15	WS_WE401: Monolithic Alternatives to PIN Diodes – RF SOI Power Limiters & Switches <i>(93) Peregrine Semiconductor</i>	WS_WE402: Design Flow and Simulation Technologies Supporting Multi-Technology RF Modules for Wireless Applications <i>(42) National Instruments</i>	WS_WE403: 5G Over-the-Air Measurements <i>(142) Rohde & Schwarz</i>	WS_WE404: RF & Microwave Coaxial Switches, How to Reach 10 Million Cycles With an Electromechanical Device <i>(145) Shanghai Radiall Electronics Co. Ltd.</i>		
16:20 - 17:00	WS_WE501: Wide Bandwidth, Low-Current Consumption Amplifier for 5G Massive MIMO Applications <i>(119) IDT</i>	WS_WE502: Challenges of Evaluating RF Performance of High Frequency Wide Bandwidth Devices <i>(87) Keysight</i>	WS_WE503: Addressing the Test Challenges of 4.5G PA and Device Measurements <i>(148) National Instruments</i>	WS_WE504: New Radiated Immunity System <i>(154) Beijing Xutec</i>		

Thursday, April 27, 2017

	Room 305A	Room 305B	Room 307A	Room 307B	
08:00 - 14:00	Registration On Site				
	Workshops				
09:00 - 09:40	WS_TH101: Innovative Solutions of Radio Signal Chain in Wireless Transmission <i>(ADI)</i>	WS_TH102: Revolutionary Filter/IPD Technology for 5G Application <i>(140) Mini-Circuits</i>	WS_TH103: A Multipurpose Millimeter Wave High Power and Low Noise GaN/Si Process for High Frequency Transmit-Receive MMICs <i>(162) Sichuan YiFeng Electronic Science & Technology Co. Ltd. Workshop</i>		
	Technical Sessions				
	Systems	High-Speed Digital Design	Test & Measurement	RF & Microwave	
09:45 - 10:05	TH_101: WiGig: 802.11ad is Coming, Test Equipment Closes Behind and What Does it Mean to Us? <i>(10) Wei Lin, National Instruments</i>	TH_102: Modeling and Calibration of High-Speed Passive Channels <i>(12) Wu Jun, Shenzhen EDADOC Technology Co. Ltd.</i>	TH_103: Measurements of Phase Noise at Frequencies Above 50 GHz <i>(120) Wolfgang Wendler, Rohde & Schwarz</i>	TH_104: Design & Build Intelligent Switching Management System for Large-Scale RF Switching <i>(118) Wang Qi, Pickering Instruments</i>	
10:10 - 10:30	TH_201: Minimizing Uncertainty in Noise Figure Measurements <i>(79) Wei Lin, National Instruments</i>	TH_202: Power and Signal Integrity Insight for DDR4/LPDDR4 Systems <i>(20) Jennie Grosslight, Keysight</i>	TH_203: An Innovative Methodology for Probe Pin Characterization with Vector Network Analyzer <i>(105) Yuk Choi Andrew KO, Keysight</i>	TH_204: An RF Solution With Design Flexibility for Mid-Tier Smartphones <i>(125) Mike Zhang, Qorvo</i>	
10:30 - 10:50	Tea/Coffee Break - Exhibition Floor				
	Test & Measurement	Radar	RF & Microwave	RF & Microwave	
10:50 - 11:10	TH_301: Understand Smearing-Effect of Time-Domain Pulse-Waves Radiated from a Wire Antenna <i>(17) Shi Pu, Wuhan University of Technology</i>	TH_302: Automotive Radar Target Simulator <i>(45) Tie Hieng Ling, Keysight</i>	TH_303: System Accuracy Verification for Real-Time Hybrid Load Pull System Under Large Mismatch Condition <i>(36) Xianfu SUN, Focus Microwaves</i>	TH_304: 5G Simulation Using Phased Array <i>(67) Zhang Shuai, Keysight</i>	
11:15 - 11:35	TH_401: On-Wafer Measurement and Analysis of Flicker Noise and Random Telegraph Noise <i>(26) Gu Feng, Keysight</i>	TH_402: Sophisticated Pulse Scenarios. How to Achieve Long Signal Play Time with High Sample Rate when ARB Size is Limited? <i>(114) Frank-W. Thümmel, Rohde & Schwarz</i>	TH_403: Applying Crest Factor Reduction (CFR) for the Partial Band of DOCSIS 3.1 System <i>(107) Maxwell Huang, Cisco Systems</i>	TH_404: One Novel In-Lab Performance Test Technique for 3D MIMO Base Stations <i>(157) Yang Huaizhi, Keysight</i>	
11:40 - 12:00	TH_501: The New Method of Nonlinear Parameter of Measurements <i>(49) Zong Huiqing, Rohde & Schwarz (China) Technology Co. Ltd.</i>	TH_502: Tackling the Test Challenges of Next Generation ADAS Vehicle Architectures <i>(84) Alejandro Buritica, National Instruments</i>	TH_503: Circularly-Polarized Antipodal Fermi Tapered Slot Antenna for Millimeter-Wave Applications <i>(110) A. Sebak, Concordia University</i>	TH_504: Using Software-Centric Solution to Build Cloud Based Test <i>(123) Shanshan Cong, Keysight</i>	

**Exhibition Hours
09:00
to
13:00**